

FCC SDoC Test Report

For

Applicant Name:

Address:

EUT Name:

Brand Name:

Model Number:

Series Model Number: Refer to section 2

SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China Smart Phone OUKITEL WP33 Pro

Issued By

Company Name:

Address:

BTF Testing Lab (Shenzhen) Co., Ltd. F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Report Number: Test Standards: BTF231110E00201 47 CFR Part 15, Subpart B

Test Conclusion: FCC ID: Test Date: Date of Issue:

Pass 2ANMU-WP33PRO 2023-11-10 to 2023-12-08 2023-12-12

Prepared By:

Date:

Approved By:

Date:

hris ab (Shenz Chris Liu / Project Enginee 2023-12-12 SZ

Ryan.CJ / EMC Manager 2023-12-12

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Revision History			
Version	Issue Date	Revisions Content	
R_V0	2023-12-12	Original	

Note: Once the revision has been made, then previous versions reports are invalid.



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1 Introduction

1.1 Identification of Testing Laboratory

Company Name: BTF Testing Lab (Shenzhen) Co., Ltd.			
Address: F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tan Community, Songgang Street, Bao'an District, Shenzhen, China			
Phone Number:	+86-0755-23146130		
Fax Number:	+86-0755-23146130		

1.2 Identification of the Responsible Testing Location

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.		
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China		
Phone Number:	+86-0755-23146130		
Fax Number:	+86-0755-23146130		
FCC Registration Number:	518915		
Designation Number:	CN1330		

1.3 Announcement

(1) The test report reference to the report template version v0.

(2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.

(3) The test report is invalid if there is any evidence and/or falsification.

(4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.

(5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.

(6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.

2 **Product Information**

2.1 Application Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD
Address:	A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.2 Manufacturer Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD
Address:	A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.3 Factory Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD
Address:	A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.4 General Description of Equipment under Test (EUT)

EUT Name:	Smart Phone
Test Model Number:	WP33 Pro
Series Model Number:	WP33, WP33 S, SP33 Ultra, WP33 TITAN
Description of Model name differentiation:	Only the model name is different, the others are the same.
Hardware Version:	HCT_V500_MBA2
Software Version:	OUKITEL_WP33_Pro_EEA_V08_20231130

2.5 Technical Information

Power Supply:	AC 120V 60Hz
Power Adaptor:	Input: 100-240V~50/60Hz 0.8A Output: 5.0V==3.0A OR 9.0V==3.0A OR 12.0V==2.75A 33.0W MAX



3 Summary of Test Results

3.1 Test Standards

The tests were performed according to following standards: **47 CFR Part 15, Subpart B:** Unintentional Radiators

3.2 Uncertainty of Test

Item	Measurement Uncertainty
Conducted Emission (150 kHz-30 MHz)	±2.64dB
Radiated Emissions (30M - 1GHz)	±4.12dB
Radiated Emissions (above 1GHz)	1-6GHz: ±3.94dB 6-18GHz: ±4.16dB

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3.3 Summary of Test Result

Item	Standard	Requirement	Result
Conducted emissions on AC mains	47 CFR Part 15, Subpart B	15.107, Class B	Pass
Radiated emissions (Below 1GHz)	47 CFR Part 15, Subpart B	15.109, Class B	Pass
Radiated emissions (Above 1GHz)	47 CFR Part 15, Subpart B	15.109, Class B	Pass



4 Test Configuration

4.1 Test Equipment List

Conducted emissions on AC mains					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Pulse Limiter	SCHWARZBECK	VTSD 9561-F	00953	2023-11-16	2024-11-15
Coaxial Switcher	SCHWARZBECK	CX210	CX210	2023-11-16	2024-11-15
V-LISN	SCHWARZBECK	NSLK 8127	01073	2023-11-16	2024-11-15
LISN	AFJ	LS16/110VAC	16010020076	2023-02-23	2024-02-22
EMI Receiver	ROHDE&SCHWA RZ	ESCI3	101422	2023-11-16	2024-11-15

Radiated emissions (I Radiated emissions (A					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Coaxial cable Multiflex 141	Schwarzbeck	N/SMA 0.5m	517386	2023-03-24	2024-03-23
Preamplifier	SCHWARZBECK	BBV9744	00246	2023-11-16	2024-11-15
RE Cable	REBES Talent	UF1-SMASMAM-1 0m	21101566	2023-11-16	2024-11-15
RE Cable	REBES Talent	UF2-NMNM-10m	21101570	2023-11-16	2024-11-15
RE Cable	REBES Talent	UF1-SMASMAM-1 m	21101568	2023-11-16	2024-11-15
RE Cable	REBES Talent	UF2-NMNM-1m	21101576	2023-11-16	2024-11-15
RE Cable	REBES Talent	UF2-NMNM-2.5m	21101573	2023-11-16	2024-11-15
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/
Horn Antenna	SCHWARZBECK	BBHA9170	01157	2023-11-16	2024-11-15
EMI TEST RECEIVER	ROHDE&SCHWA RZ	ESCI7	101032	2023-11-16	2024-11-15
SIGNAL ANALYZER	ROHDE&SCHWA RZ	FSQ40	100010	2023-11-16	2024-11-15
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/
Broadband Preamplilifier	SCHWARZBECK	BBV9718D	00008	2023-03-24	2024-03-23
Horn Antenna	SCHWARZBECK	BBHA9120D	2597	2022-05-22	2024-05-21
EZ_EMC	Frad	FA-03A2 RE+	/	/	/
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/
Log periodic antenna	SCHWARZBECK	VULB 9168	01328	2023-11-16	2024-11-15



4.2 Test Auxiliary Equipment

Title	Manufacturer	Model No.	Serial No.
/	/	/	/

4.3 Test Modes

No.	Test Modes	Description
TM1	Charging + Video recording	
TM2	Charging + Video play	
TM3	Date transmission	



5 Emission Test Results (EMI)

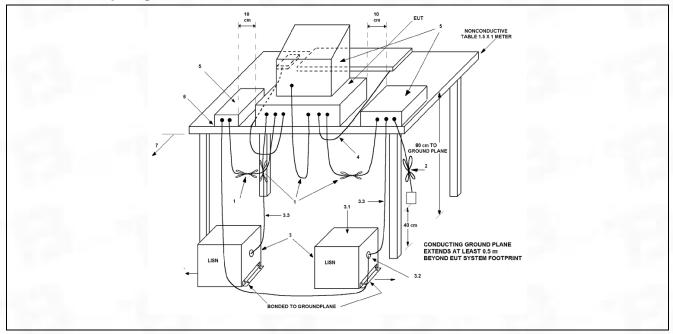
5.1 Conducted emissions on AC mains

Test Requirement:	15.107, Class B					
Test Method:	ANSI C63.4-2014					
	Frequency of emission (MHz)	Conducted limit (dBµV)			
		Quasi-peak	Average			
Toot Limit	0.15-0.5	66 to 56*	56 to 46*			
Test Limit:	0.5-5	56	46			
	5-30	60	50			
	*Decreases with the logarithm of the frequency.					
Procedure:	An initial pre-scan was performed we measurement were performed at the were detected. Remark: Level= Read Level+ Cable	ne frequencies with ma				

5.1.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24 °C
Humidity:	48.6 %
Atmospheric Pressure:	1010 mbar

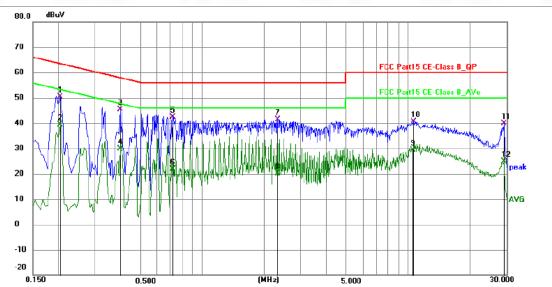
5.1.2 Test Setup Diagram:





5.1.3 Test Data:

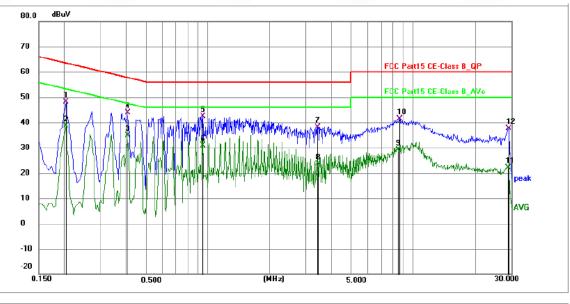
TM1 / Line: Line



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1	0.2040	39.90	10.57	50.47	63.45	-12.98	QP	Р	
2	0.2040	28.78	10.57	39.35	53.45	-14.10	AVG	Ρ	
3 *	0.3975	34.21	11.19	45.40	57.91	-12.51	QP	Р	
4	0.3975	18.64	11.19	29.83	47.91	-18.08	AVG	Р	
5	0.7170	31.41	10.94	42.35	56.00	-13.65	QP	Р	
6	0.7170	10.92	10.94	21.86	46.00	-24.14	AVG	Р	
7	2.3145	30.69	10.67	41.36	56.00	-14.64	QP	Р	
8	2.3145	9.38	10.67	20.05	46.00	-25.95	AVG	Р	
9	10.5450	18.52	10.85	29.37	50.00	-20.63	AVG	Р	
10	10.6170	29.69	10.85	40.54	60.00	-19.46	QP	Р	
11	29.2110	28.56	11.21	39.77	60.00	-20.23	QP	Р	
12	29.2110	13.62	11.21	24.83	50.00	-25.17	AVG	Р	



TM1 / Line: Neutral



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1	0.2040	37.45	10.57	48.02	63.45	-15.43	QP	Р	
2	0.2040	28.11	10.57	38.68	53.45	-14.77	AVG	Р	
3 *	0.4061	23.59	11.20	34.79	47.73	-12.94	AVG	Р	
4	0.4065	32.76	11.20	43.96	57.72	-13.76	QP	Р	
5	0.9465	31.59	10.67	42.26	56.00	-13.74	QP	Р	
6	0.9465	20.11	10.67	30.78	46.00	-15.22	AVG	Р	
7	3.4215	27.59	10.64	38.23	56.00	-17.77	QP	Р	
8	3.4440	13.11	10.64	23.75	46.00	-22.25	AVG	Р	
9	8.5424	18.39	10.82	29.21	50.00	-20.79	AVG	Р	
10	8.5740	30.52	10.82	41.34	60.00	-18.66	QP	Р	
11	28.9815	10.95	11.21	22.16	50.00	-27.84	AVG	Р	
12	29.2110	26.51	11.21	37.72	60.00	-22.28	QP	Р	



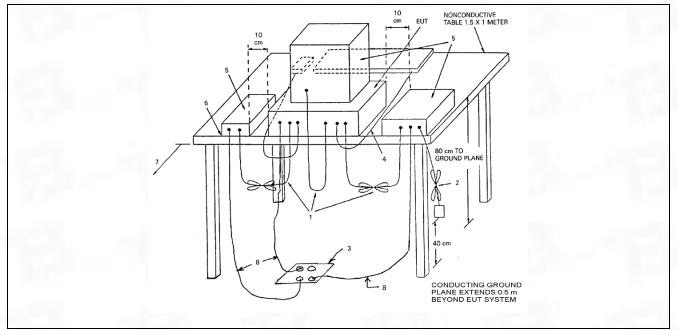
5.2 Radiated emissions (Below 1GHz)

Test Requirement:	15.109, Class B								
Test Method:	ANSI C63.4-2014								
Test Limit:	Except for Class A digital devices, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:								
	Frequency of emission (MHz)	Field stro @3m	ength	Field str	ength @10m				
		(uV/m)	(dBuV/ m)	(uV/m)	(dBuV/m)				
	30 – 88	100	40	30	29.5				
	88 – 216	150	43.5	45	33.1				
	216 – 960	200	46	60	35.6				
	Above 960	500	54	150	43.5				
Procedure:	An initial pre-scan was perform peak detection mode. Quasi-p peak sweep graph. The EUT v orthogonal polarities. Remark: Level= Read Level+	eak measure vas measure	ements wer d by BiCor	iLog anter	ed based on the nna with 2				

5.2.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24 °C
Humidity:	48.6 %
Atmospheric Pressure:	1010 mbar

5.2.2 Test Setup Diagram:





5.2.3 Test Data:

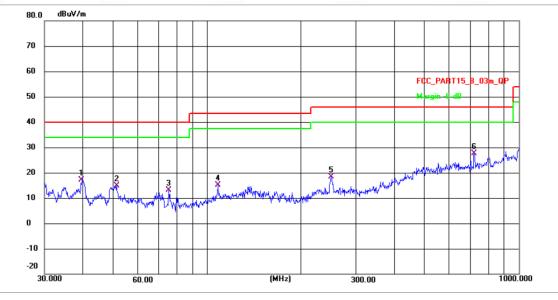


dBu∀/m 80.0 70 60 FCC_PART15 50 40 30 20 10 0 -10 -20 30.000 (MHz) 1000.000 300.00 60.00

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	39.5757	36.14	-18.41	17.73	40.00	-22.27	QP	Р
2	49.9689	32.02	-18.27	13.75	40.00	-26.25	QP	Р
3	136.9391	43.30	-27.90	15.40	43.50	-28.10	QP	Р
4	249.4250	42.71	-25.85	16.86	46.00	-29.14	QP	Р
5	486.4614	43.86	-21.45	22.41	46.00	-23.59	QP	Р
6 *	721.7259	50.06	-23.68	26.38	46.00	-19.62	QP	Р



TM1 / Polarization: Vertical



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	39.7146	37.65	-20.53	17.12	40.00	-22.88	QP	Р
2	51.2106	35.24	-20.30	14.94	40.00	-25.06	QP	Р
3	75.4464	33.07	-19.90	13.17	40.00	-26.83	QP	Р
4	108.2667	43.33	-28.15	15.18	43.50	-28.32	QP	Р
5	249.8627	44.30	-25.85	18.45	46.00	-27.55	QP	Р
6 *	720.4616	51.39	-23.66	27.73	46.00	-18.27	QP	Р



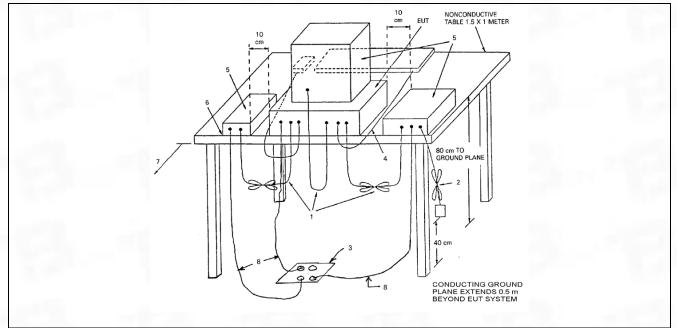
5.3 Radiated emissions (Above 1GHz)

Test Requirement:	15.109, Class B							
Test Method:	ANSI C63.4-2014							
	Frequency of emission (MHz)	Field stren	gth @3m					
Test Limit:	and the second se	Average (uV/m)						
	Above 1GHz	500	54	74				
Procedure:	An initial pre-scan was performed i peak detection mode. For below 10 conducted based on the peak swee antenna with 2 orthogonal polarities were conducted based on the peak antenna with 2 orthogonal polarities Remark: Level= Read Level+ Cable	GHz test, Quas op graph. The s. For above 10 sweep graph. s.	si-peak measure EUT was measu GHz test, Averaç The EUT was n	ements were ired by BiConiLog ge measurements neasured by Horr				

5.3.1 E.U.T. Operation:

Operating Environment:					
Temperature:	24 °C				
Humidity:	48.6 %				
Atmospheric Pressure:	1010 mbar				

5.3.2 Test Setup Diagram:





5.3.3 Test Data:

TM1 / Polarization: Horizontal

	No.	Frequency	Reading	Factor	Level	Limit	Margin	Detector	P/F
		(MHz)	(dBuV)	(dB/m)	(dBuV/m)	(dBuV/m)	(dB)		
	1	1206.687	80.45	-29.71	50.74	74.00	-23.26	peak	Р
	2	1457.716	82.24	-30.22	52.02	74.00	-21.98	peak	Р
	3	1677.042	83.90	-30.44	53.46	74.00	-20.54	peak	Р
	4	2657.312	80.47	-31.22	49.25	74.00	-24.75	peak	Р
	5	3790.982	82.50	-31.71	50.79	74.00	-23.21	peak	Р
	6	5081.712	84.91	-30.80	54.11	74.00	-19.89	peak	Р

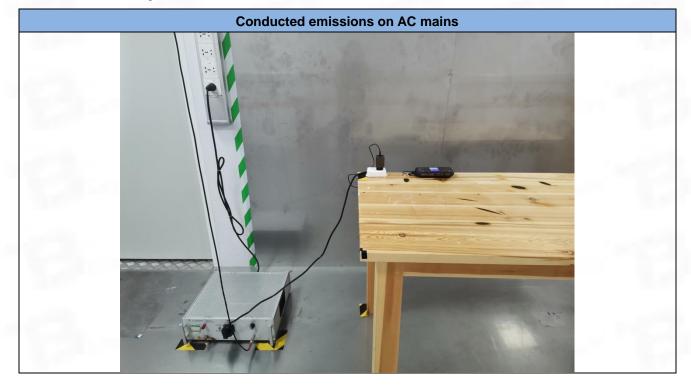


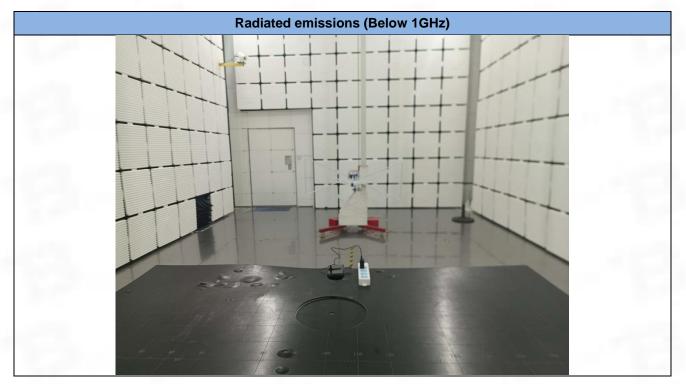
TM1 / Polarization: Vertical

No.	Frequency	Reading	Factor	Level	Limit	Margin	Detector	P/F
	(MHz)	(dBuV)	(dB/m)	(dBuV/m)	(dBuV/m)	(dB)		
1	1436.950	<mark>81.13</mark>	-29.78	51.35	74.00	-22.65	peak	Ρ
2	1687.979	82.92	-30.29	52.63	74.00	-21.37	peak	Р
3	1907.305	<mark>84.5</mark> 8	-30.51	54.07	74.00	-19.93	peak	Р
4	2887.575	<mark>81.15</mark>	-31.29	49.86	74.00	-24.14	peak	Р
5	4021.245	<mark>83.1</mark> 8	-31.78	51.40	74.00	-22.60	peak	Р
6	5311.975	85.59	-30.87	54.72	74.00	-19.28	peak	Р
	1 2 3 4 5	No. (MHz) 1 1436.950 2 1687.979 3 1907.305 4 2887.575 5 4021.245	No. (MHz) (dBuV) 1 1436.950 81.13 2 1687.979 82.92 3 1907.305 84.58 4 2887.575 81.15 5 4021.245 83.18	No. (MHz) (dBuV) (dB/m) 1 1436.950 81.13 -29.78 2 1687.979 82.92 -30.29 3 1907.305 84.58 -30.51 4 2887.575 81.15 -31.29 5 4021.245 83.18 -31.78	No. (MHz) (dBuV) (dB/m) (dBuV/m) 1 1436.950 81.13 -29.78 51.35 2 1687.979 82.92 -30.29 52.63 3 1907.305 84.58 -30.51 54.07 4 2887.575 81.15 -31.29 49.86 5 4021.245 83.18 -31.78 51.40	No. (MHz) (dBuV) (dB/m) (dBuV/m) (dBuV/m) 1 1436.950 81.13 -29.78 51.35 74.00 2 1687.979 82.92 -30.29 52.63 74.00 3 1907.305 84.58 -30.51 54.07 74.00 4 2887.575 81.15 -31.29 49.86 74.00 5 4021.245 83.18 -31.78 51.40 74.00	No. (MHz) (dBuV) (dB/m) (dBuV/m) (dBuV/m) (dB) 1 1436.950 81.13 -29.78 51.35 74.00 -22.65 2 1687.979 82.92 -30.29 52.63 74.00 -21.37 3 1907.305 84.58 -30.51 54.07 74.00 -19.93 4 2887.575 81.15 -31.29 49.86 74.00 -24.14 5 4021.245 83.18 -31.78 51.40 74.00 -22.60	No. (MHz) (dBuV) (dB/m) (dBuV/m) (dBuV/m) (dB Detector 1 1436.950 81.13 -29.78 51.35 74.00 -22.65 peak 2 1687.979 82.92 -30.29 52.63 74.00 -21.37 peak 3 1907.305 84.58 -30.51 54.07 74.00 -19.93 peak 4 2887.575 81.15 -31.29 49.86 74.00 -24.14 peak 5 4021.245 83.18 -31.78 51.40 74.00 -22.60 peak

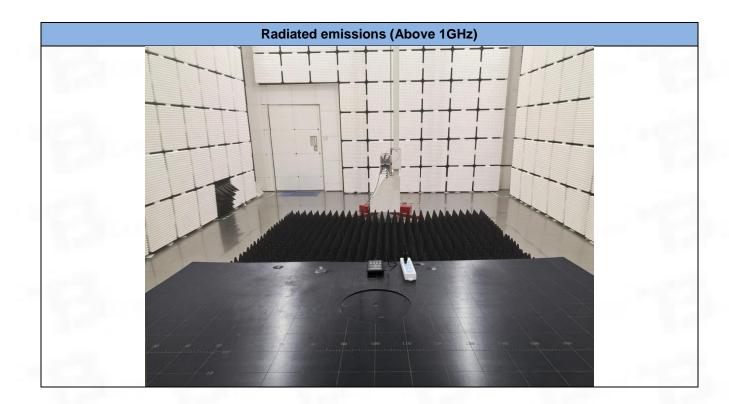


6 Test Setup Photos

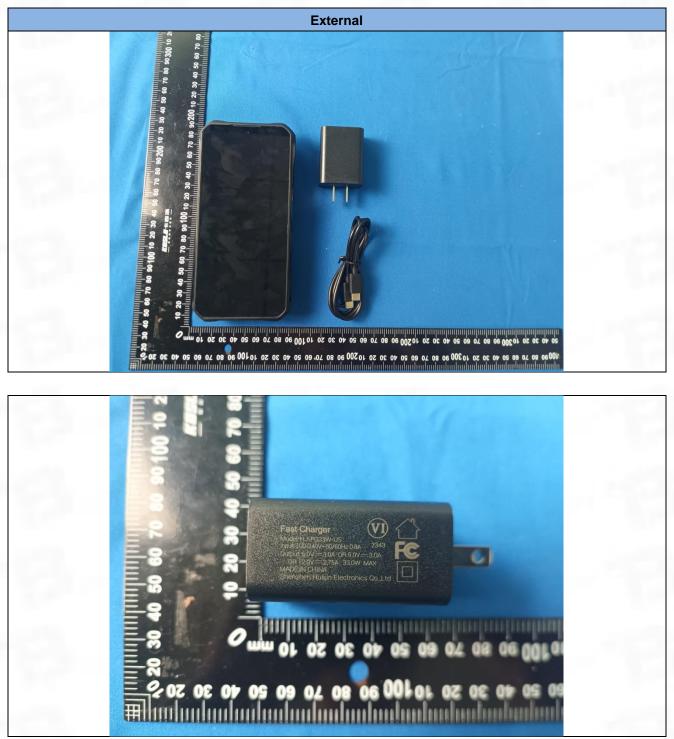








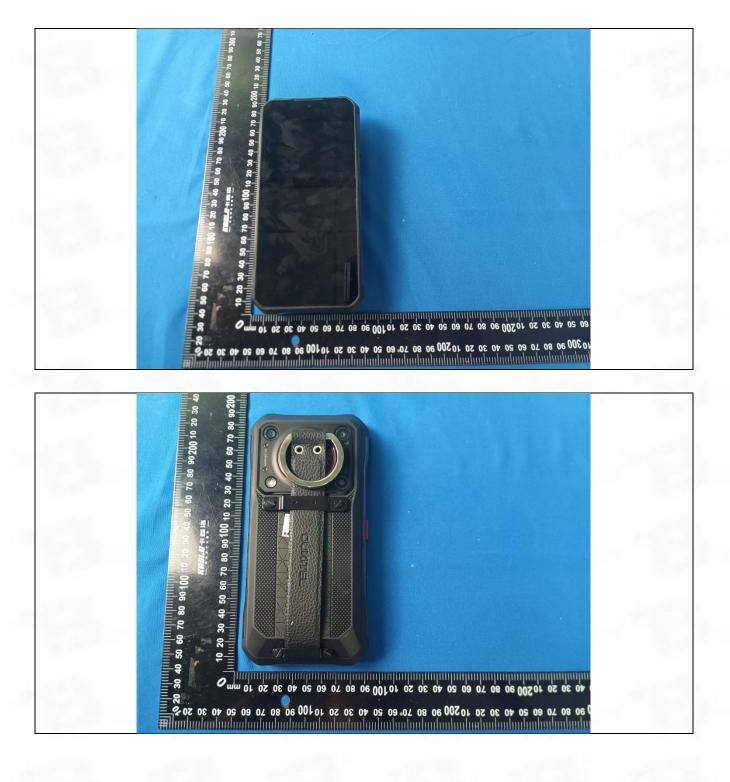




7 EUT Constructional Details (EUT Photos)

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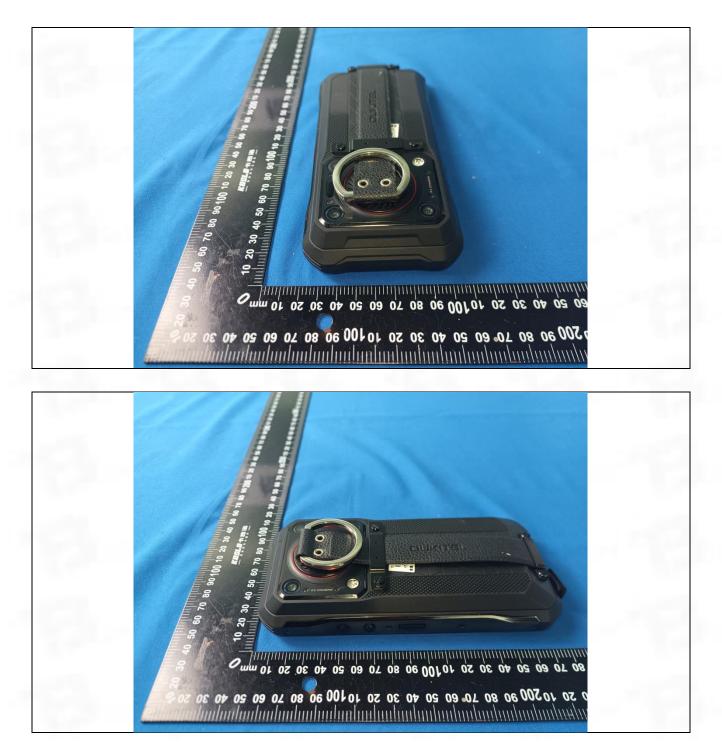




20 50 10 500 30 80 10. 60 20 40 30 50 10100 30 80 10 60 20 40 30

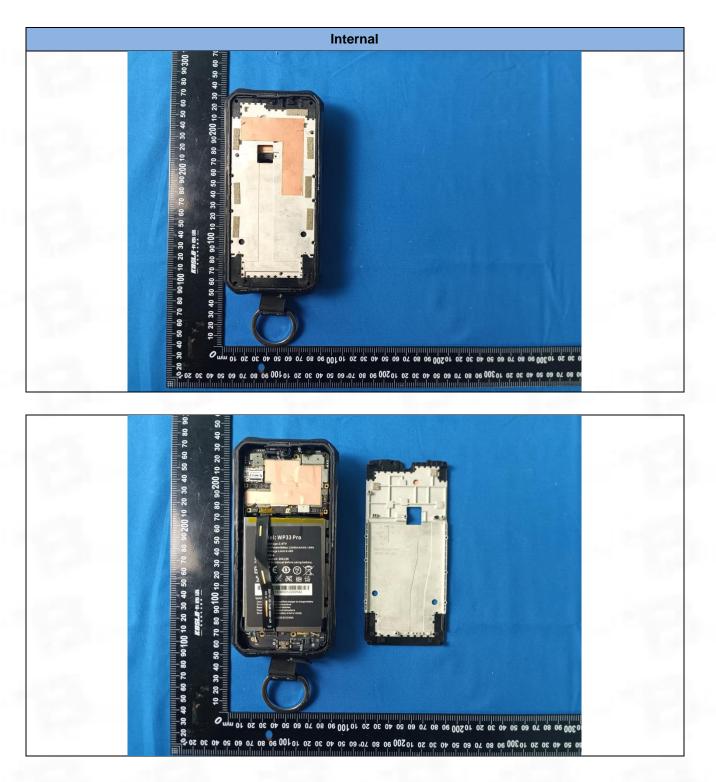
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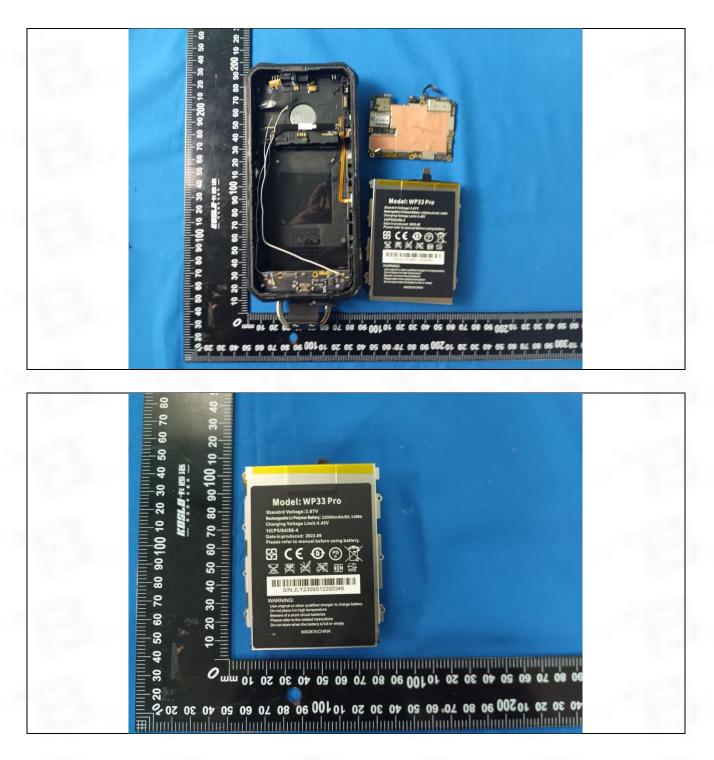
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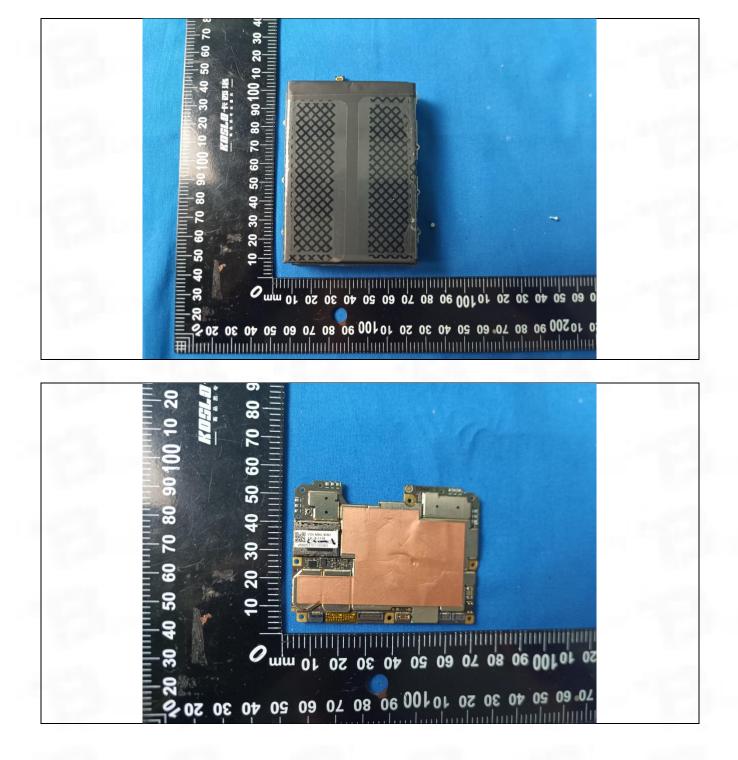




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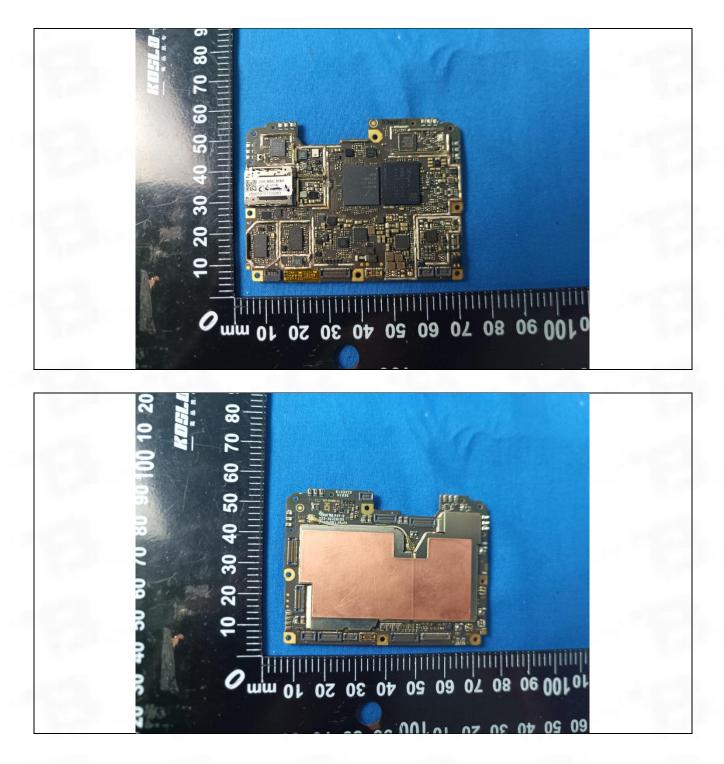




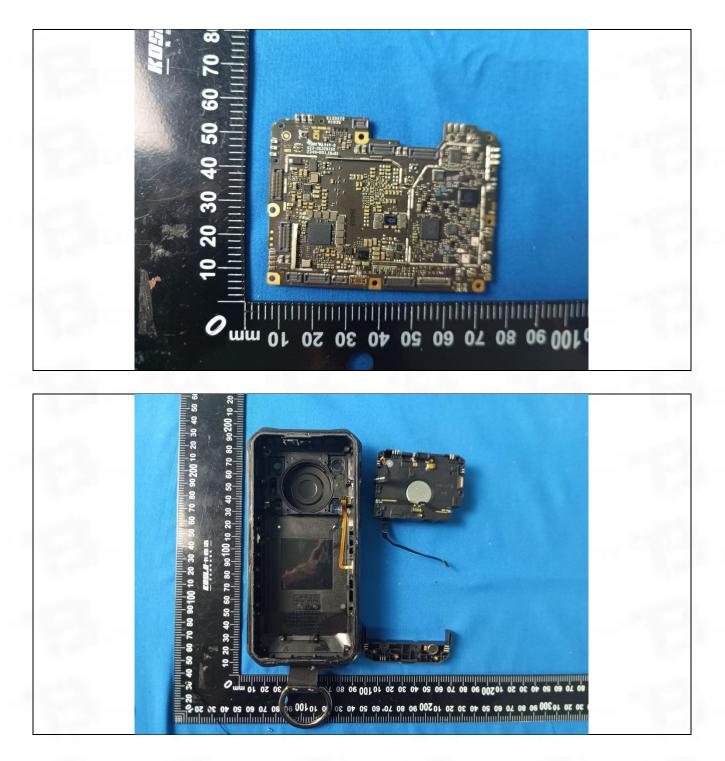
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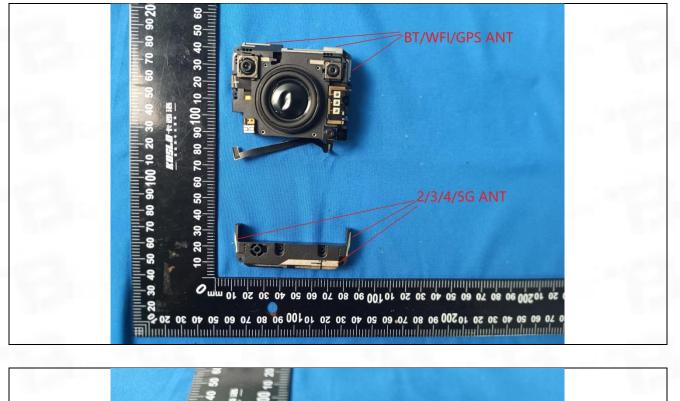






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